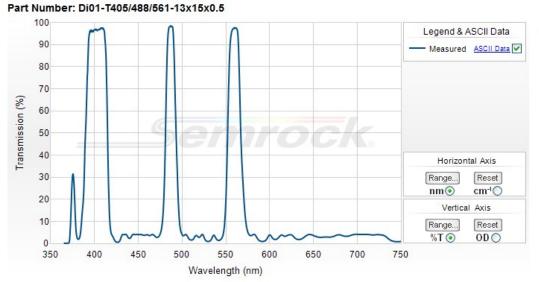
405/488/561 nm Yokogawa dichroic beamsplitter





Semrock, Inc

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(within US and Canada)

Your filter spectrum may differ slightly from the typical spectrum above, but is certified to meet the optical specifications noted below.



405/488/561 nm Yokogawa dichroic beamsplitter

Combining superior performance with exceptional durability, these filters are specifically optimized for use with all Yokogawa CSU spinning-disk scan head system configurations.

Part Number	Size	Price1	Stock Status
Di01-T405/488/561-13x15x0.5	13 mm x 15 mm x 0.5 mm (unmounted)	\$665	In Stock

This part is not available for custom sizing.

1) US domestic pricing only. If you are ordering from outside the US, please contact your nearest regional distributor for the correct list price.

Optical Specifications

Specification	Value	
Reflection Band 1	Ravg > 95% 442 – 473 nm	
Edge Wavelength 1	405 nm	
Transmission Band 1	Tavg $> 90\% 400 - 410 \text{ nm}$	
Reflection Band 2	Ravg > 95% 503 – 544 nm	
Edge Wavelength 2	488 nm	
Transmission Band 2	Tavg > 90% 488 nm	
Reflection Band 3	Ravg > 95% 578 - 750 nm	
Edge Wavelength 3	561 nm	
Transmission Band 3	Tavg > 90% 561 nm	

General Filter Specifications

Specification	Value
Laser Wavelength 1	400 – 410 nm
Laser Wavelength 2	488 nm
Laser Wavelength 3	561 nm
Angle of Incidence	45 ± 1.5 degrees
Cone Half-angle	0.5 degrees
Optical Damage Rating	Not Tested
Flatness	Laser Flat
Steepness	Steep
Effective Index	1.81

Physical Filter Specifications (applies to standard sized parts; contact us regarding other sizes)

Specification Value

Transverse Dimensions (L x W)	13.0 mm x 15.0 mm
Transverse Tolerance	+ 0.0 / - 0.2 mm
Filter Thickness (unmounted)	0.5 mm
Filter Thickness Tolerance (unmounted)	± 0.02 mm
Clear Aperture	≥ 80% (elliptical)
Scratch-Dig	40-20
Substrate Type	Fused Silica
Substrate Thickness (unmounted)	0.5 mm
Substrate Thickness Tolerance (unmounted)	± 0.02 mm
Orientation	Unmarked (reflective coating towards sample)